

<b>Notice of References Cited</b>	Application/Control No. 10/693,736		Applicant(s)/Patent Under Reexamination YUAN ET AL.	
	Examiner CHAU NGUYEN		Art Unit 2176	Page 1 of 1

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*	B	US-2003/0135538	07-2003	Takeuchi et al.	709/200
*	C	US-2005/0262141	11-2005	Miyamori, Hisashi	707/104.1
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**NON-PATENT DOCUMENTS**

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